

## **Excellent Integrated System Limited**

Stocking Distributor

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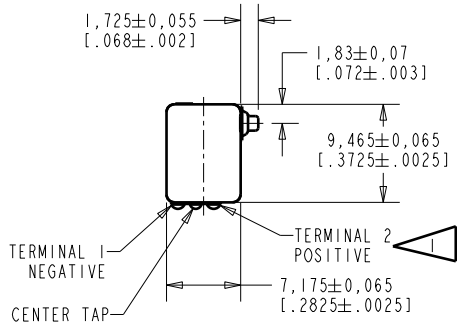
[Knowles](#)

[CI-28267-000](#)

For any questions, you can email us directly:

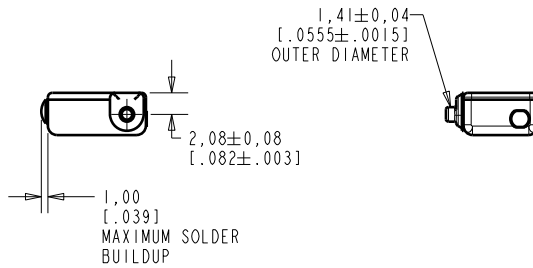
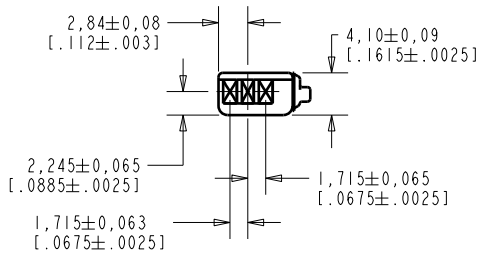
[sales@integrated-circuit.com](mailto:sales@integrated-circuit.com)

**CI-28267-000**  
SHT 1.1



NOTES:

▲ A POSITIVE GOING VOLTAGE AT TERMINAL 2, RELATIVE TO TERMINAL 1, CAUSES AN INCREASE IN PRESSURE AT THE SOUND OUTLET.



SCALE 2:1

DIMENSIONS IN MILLIMETERS [INCHES]

Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
E	C10114321	12-12-12	Active	E
D	C10111948	12-30-10		

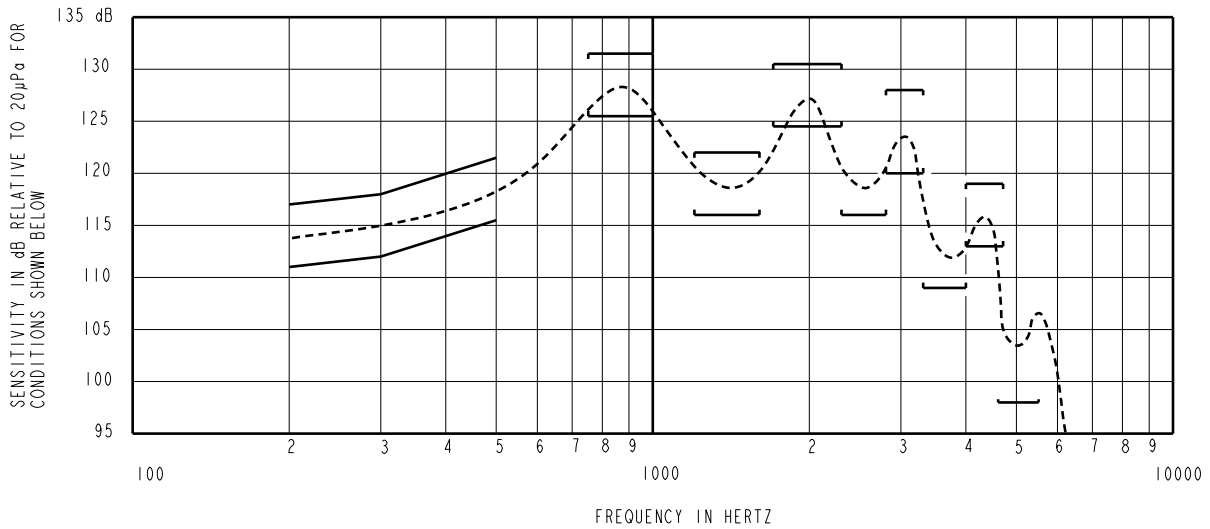
**KNOWLES ELECTRONICS**  
ITASCA, ILLINOIS U.S.A.

SCALE:	2:1	DR. BY	DATE
DO NOT SCALE DRAWING		LSY	10-13-06
TITLE:		CK. BY	DATE
RECEIVER	CI-28267-000	GJP	10-13-06
OUTLINE DRAWING	SHT 1.1	APP. BY	DATE
		GJP	10-13-06

NO DAMPING

CI-28267-000

SHEET 2.1



NOTES:

1. MEASUREMENTS MADE USING 8mm [.315"] X 1mm [.039"] ID + 28mm [1.10 ] X 1.5mm [.059 ] ID EAR HOOK SIMULATOR INTO 25mm [.984"] OF 2mm [.079"] ID TUBE + 18mm [.709"] OF 3mm [.118"] ID TUBE + 2 CM<sup>3</sup> CAVITY ANSI S3.6 TYPE HA-3 (IEC 60318-5).

2. SENSITIVITY

FREQUENCY	MIN.	MAX.
200	111.0	117.0
300	112.0	118.0
500	115.5	121.5
750-1000	125.5	131.5
1200-1600	116.0	122.0
1700-2300	124.5	130.5
2300-2800	116.0	---
2800-3300	120.0	128.0
3300-4000	109.0	---
4000-4700	113.0	119.0
4800-5500	98.0	---

3. RESPONSE, IMPEDANCE, AND DISTORTION MEASUREMENTS MADE USING THE ELECTRICAL TEST CONDITIONS SHOWN BELOW.

4. INDIVIDUAL SPECIFICATIONS.

PORT LOCATION	ELECTRICAL TEST CONDITIONS				IMPEDANCE @ 500 Hz OHMS ± 15%	DCR @ 20°C OHMS ± 10%	DISTORTION	
	RESPONSE & IMPEDANCE		DISTORTION				MAX. %	FREQ. Hz
	AC mA RMS	DC mA	AC mA RMS	DC mA				
2S	2.0	0.0	4.0	0.0	174	75	10	500

5. ELECTRICAL SOURCE IMPEDANCE MUST BE GREATER THAN 20 TIMES STATED IMPEDANCE FOR TEST CONDITIONS ABOVE.

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E	CI0114321	12-12-12	Active	E
D	CI0111948	12-30-10		

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WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION

DR. BY	DATE
LSY	10-13-06
CK. BY	DATE
GJP	10-13-06
APP. BY	DATE

TITLE: RECEIVER

CI-28267-000